


<b>Search Notes</b>  	<b>Application/Control No.</b>  10575093	<b>Applicant(s)/Patent Under Reexamination</b>  MURAKATA ET AL.
	<b>Examiner</b>  Loewe, Sun Jae Y	<b>Art Unit</b>  1626

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
STN structure	8/27/2007	sl
palm inventor (all inventors)	8/27/2007	sl
STN: registry & caplus updated	5-14-2008	sl
PALM all inventors updated	5-14-2008	sl

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner